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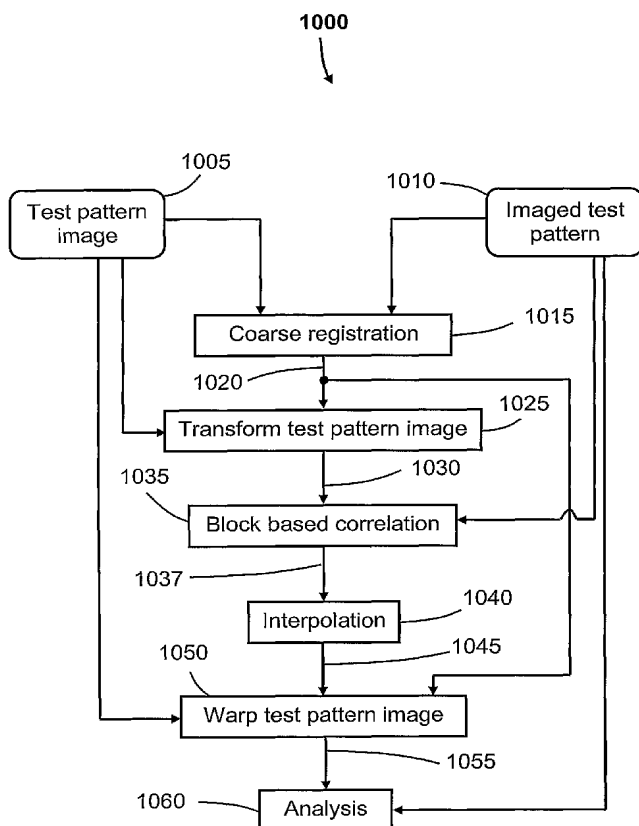
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(54) Title: IMAGING SYSTEM PERFORMANCE MEASUREMENT



(57) Abstract: A method (1000) of measuring performance parameters of an imaging device (120, 160) is disclosed. The method (1000) maintains a test pattern image (1005), the test pattern image (1005) comprising alignment features and image analysis features. A test chart (110, 170) containing a representation of the test pattern image is next imaged using the imaging device (120, 160) to form a second image (1010). The test pattern image (1005) and the second image (1010) are then registered using region based matching (1035) operating on the alignment features. Finally, the performance parameters are measured by analysing (1060) the image analysis features.



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